

Multi-parameter Magnetic Material Characterization for High Power Medium Frequency Converters

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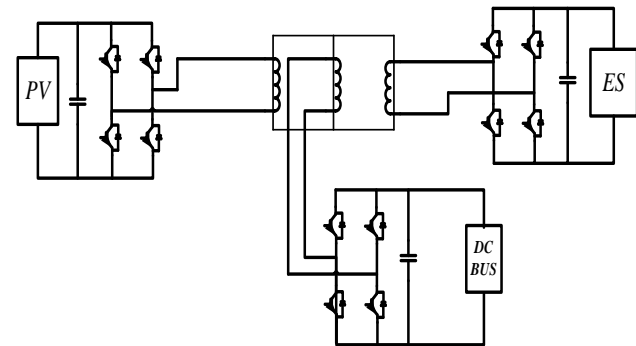
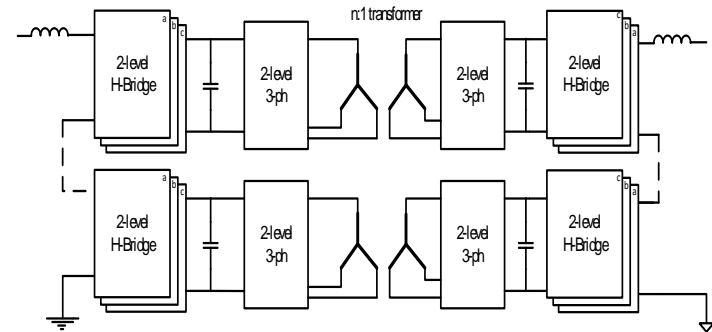
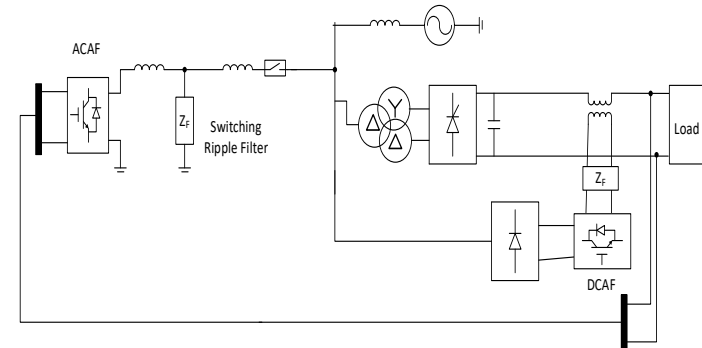
²National Energy Technology Labs

Motivation

- Static Core Parameters
 - Volume
 - Cross Sectional Area
 - Magnetic Length
- Well Known Variables
 - Sinusoidal Core Loss
- Less Known Variables
 - Non-Sinusoidal Core Loss, Trapezoidal
 - Thermal Rise
 - Operating Point Dependent Permeability

Application Space Examples

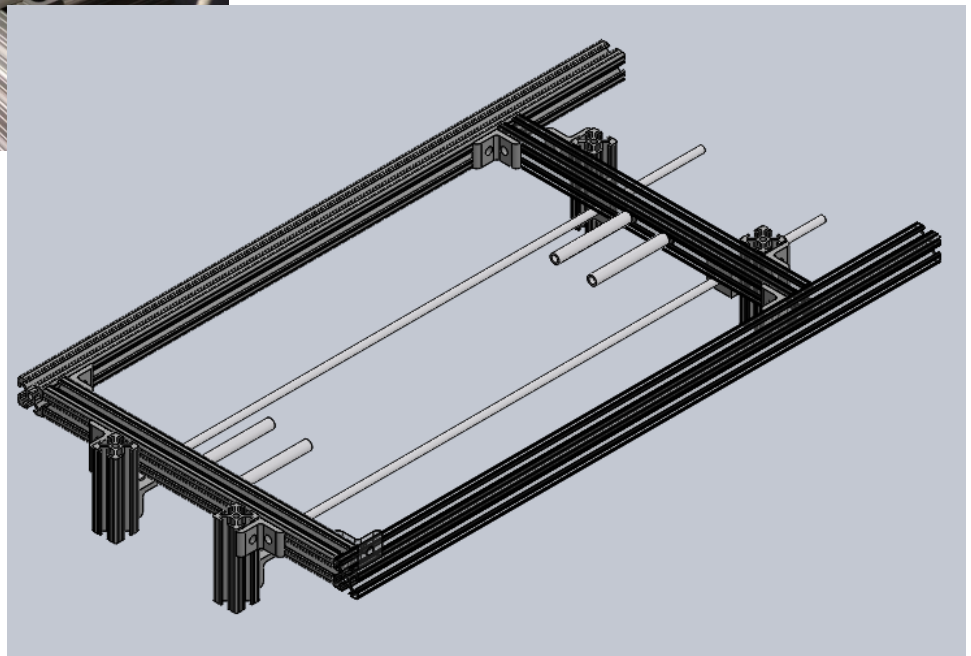
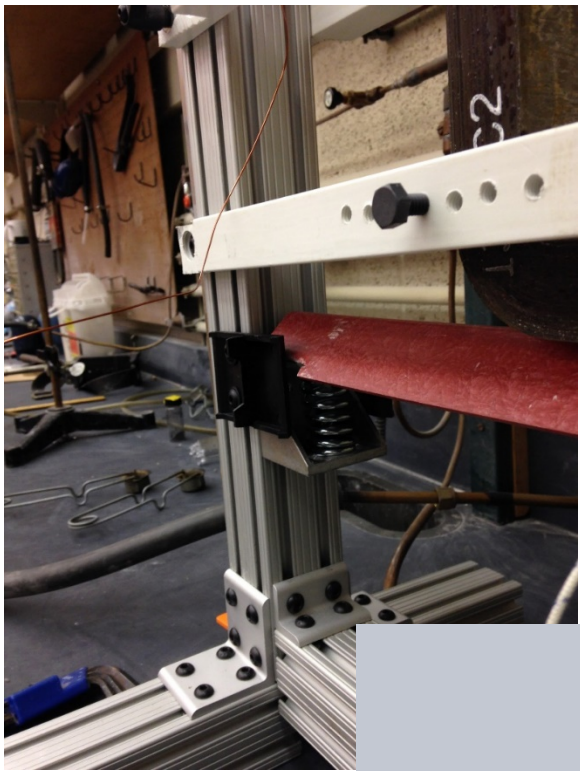
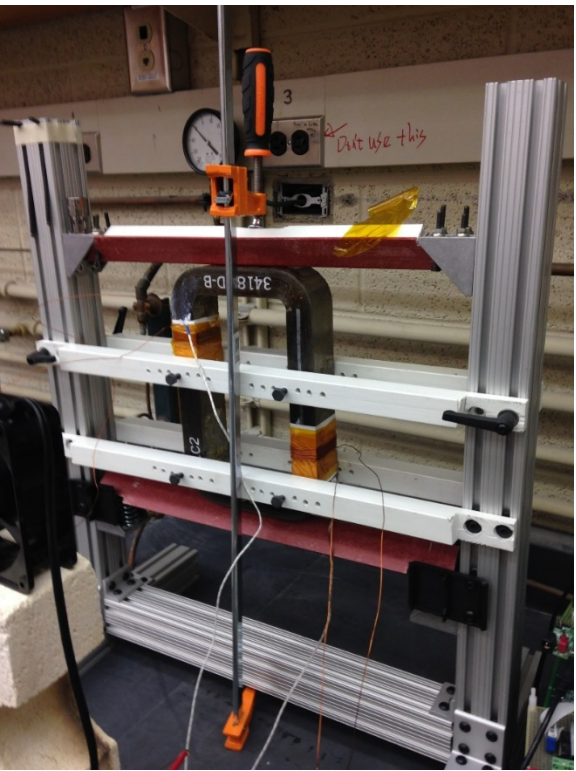
- AC and DC Active Filters
- Solid State Transformers
- Dual- / Tri- Active Bridge



Test System Requirements

- Minimal Testing Losses / Impact
- High Power
 - Energize / Study Cores for 100kVA Systems
 - 1.2 kV, 1.7 kV as Low Voltage Rating
 - High Testing Temperatures > 100 C ~200 C
- Medium Frequency
 - 1 kHz to 500 kHz
- Application Specific Excitation
 - Trapezoidal, Triangular, Sinusoidal, Arbitrary Excitation Shape
 - Blanking Time, Deadband

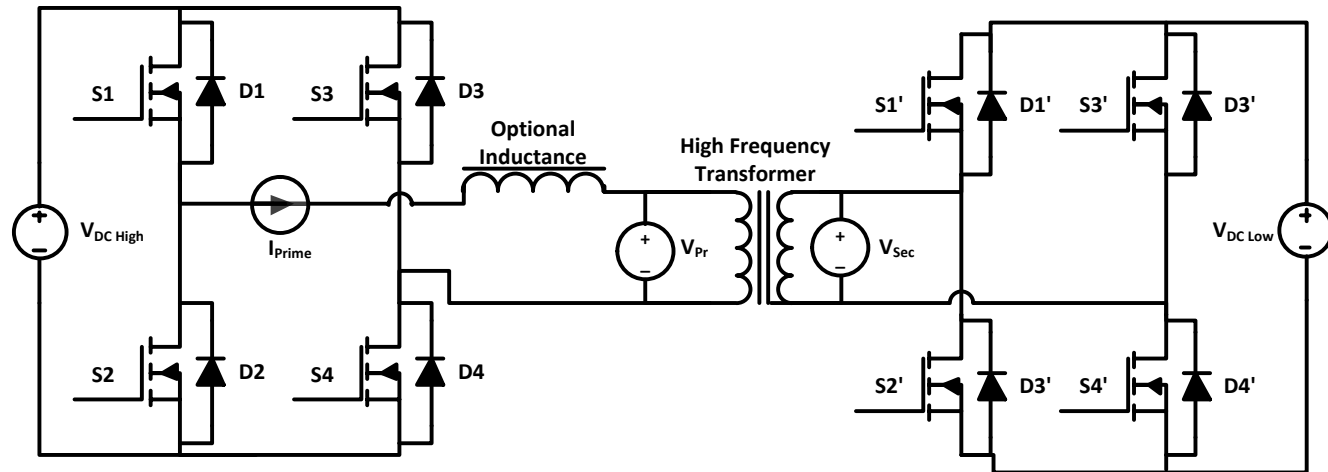
Core Harness for Constant Force Study



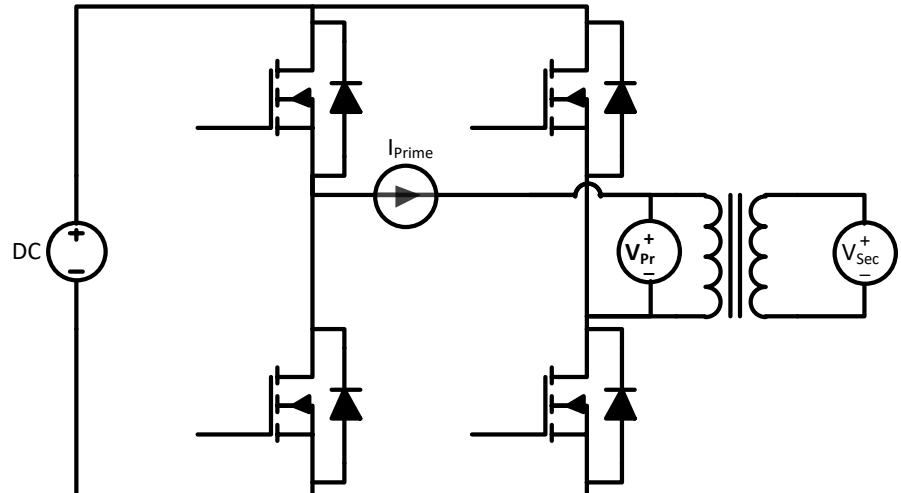
High Temperature

Historical Approach to Core Loss

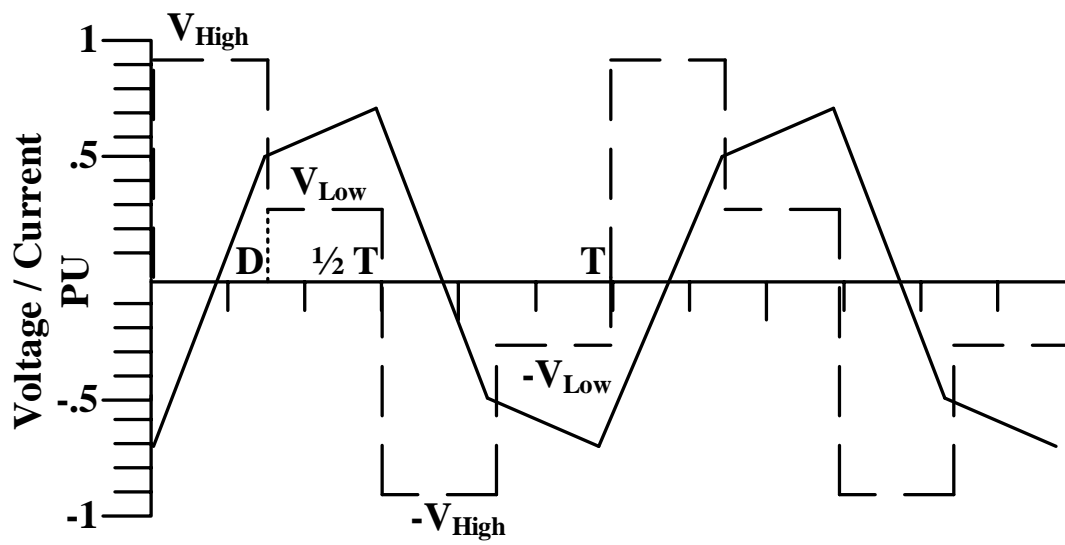
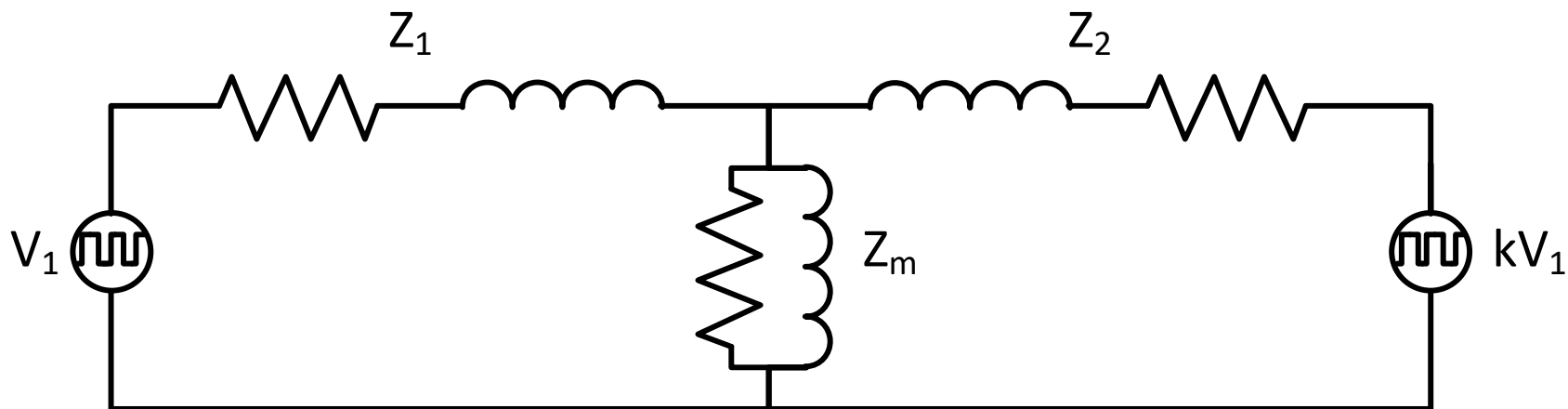
Akagi



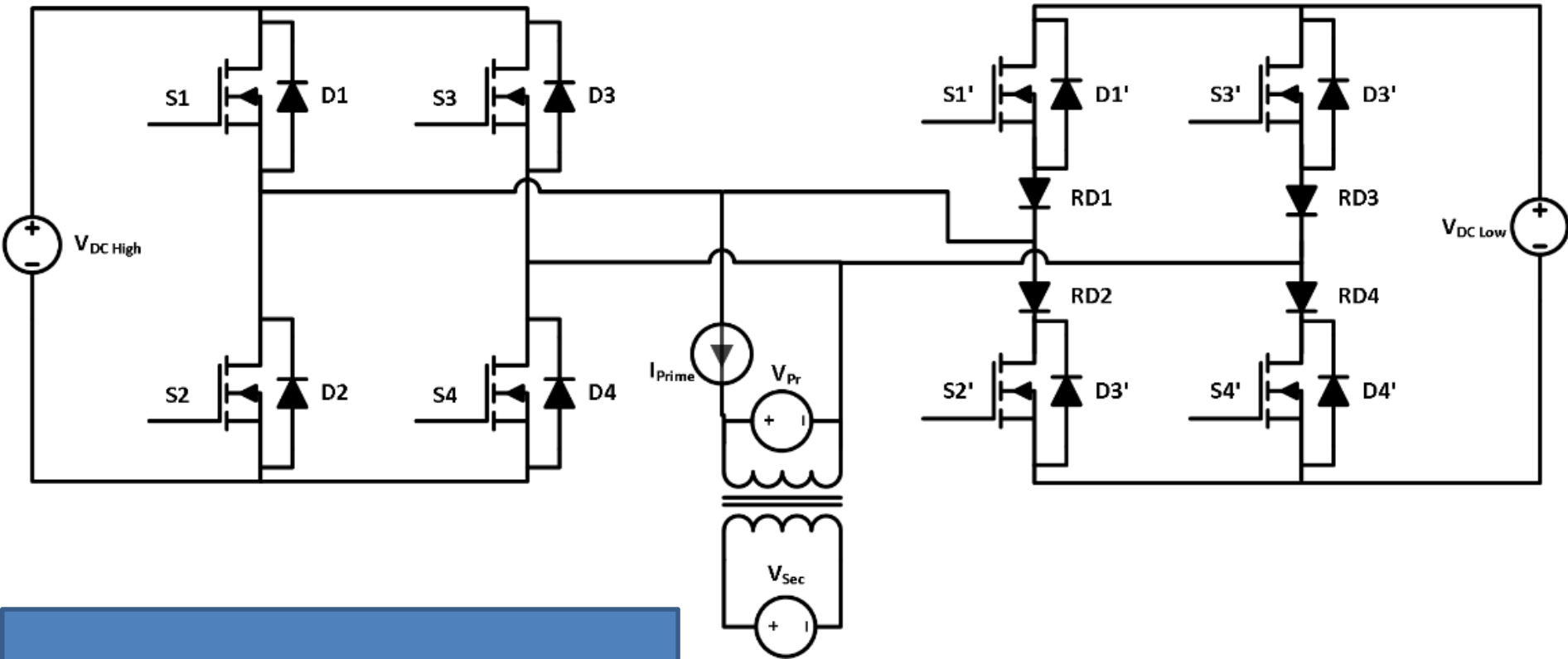
Kolar / Rik de Doncker /
Sullivan et. al.



Transformer Voltages for Trapezoidal Excitation – DAB Motivation



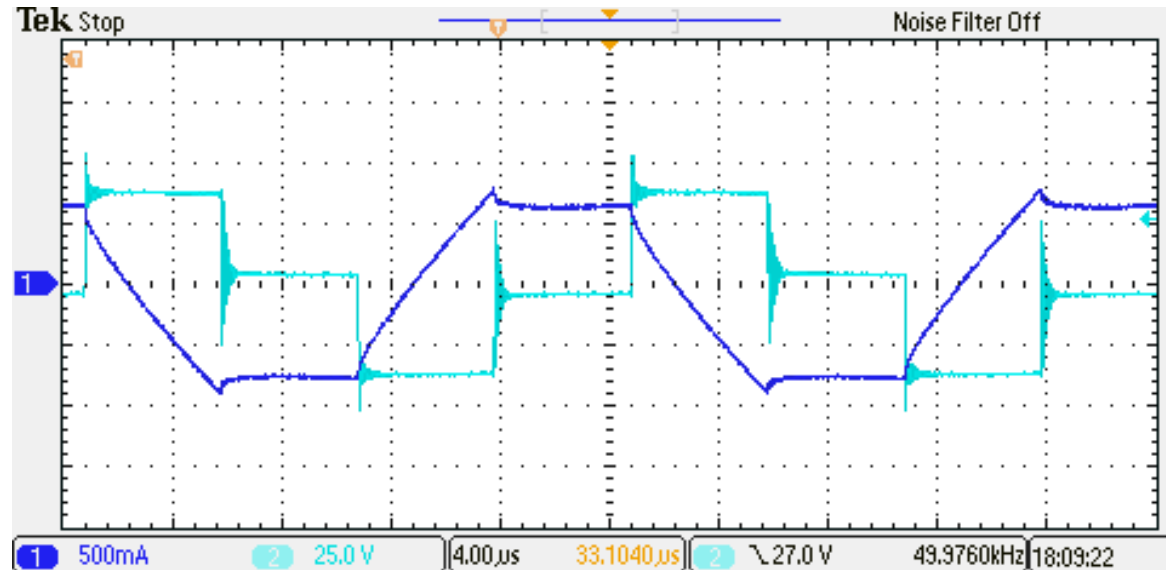
Core Test Circuit for Trapezoidal Excitation



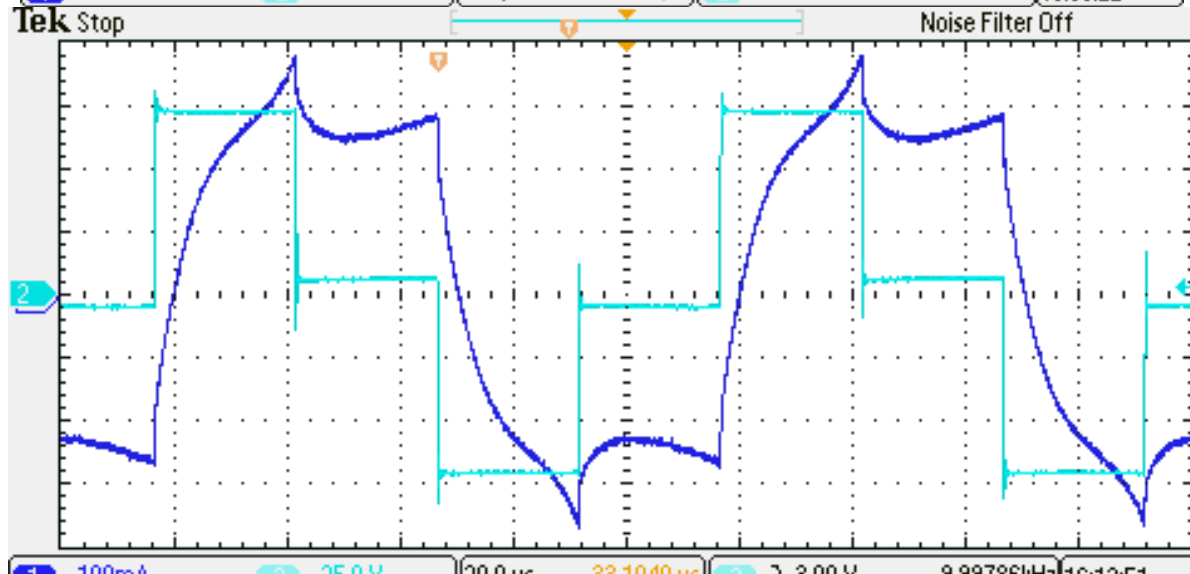
Provisional Patent: 98192/1063283,
62/583,843

Dual Voltage Source Core Tester

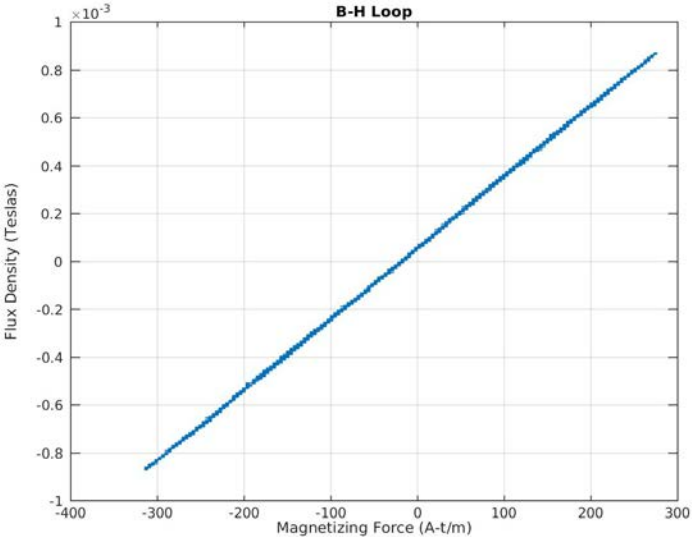
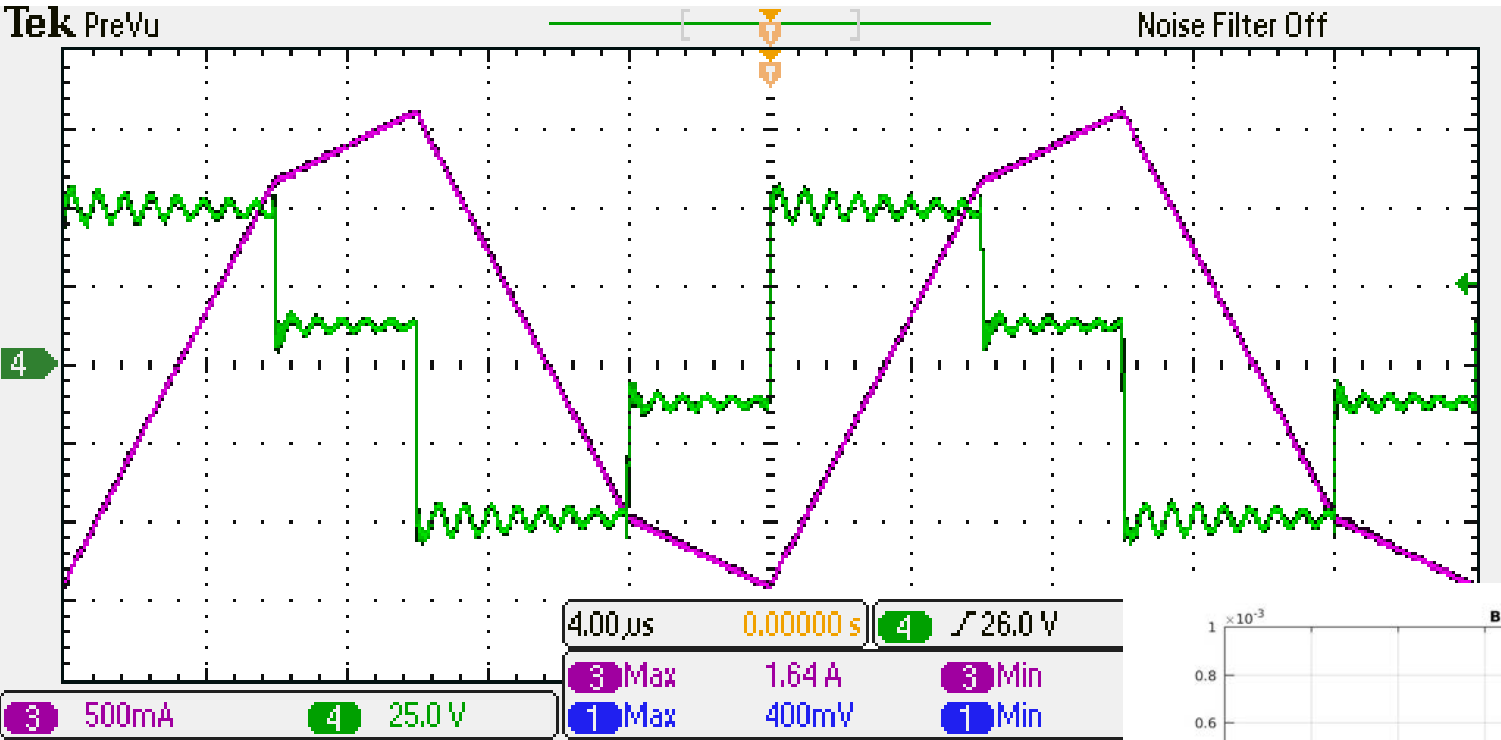
Flat Top Excitation



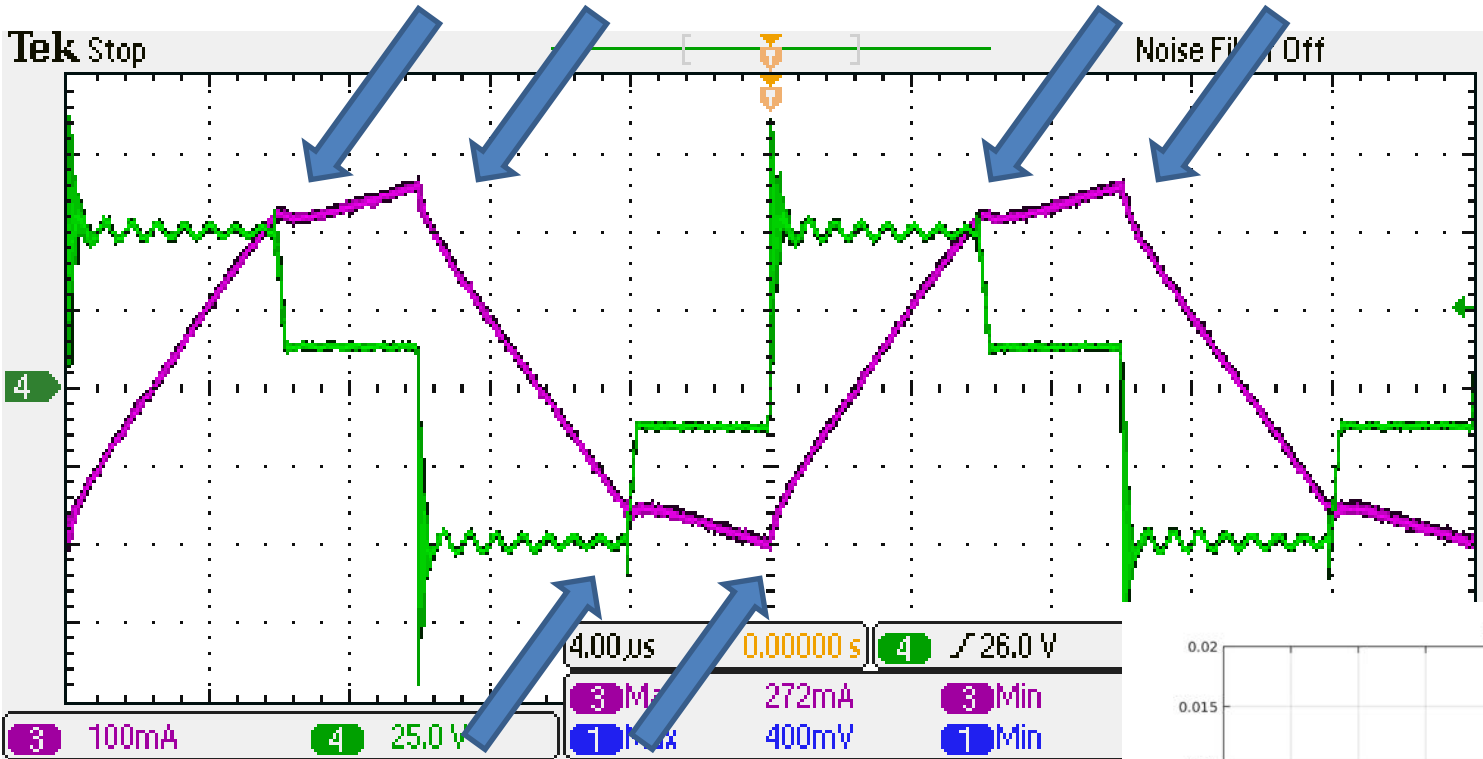
Dual Slope Excitation



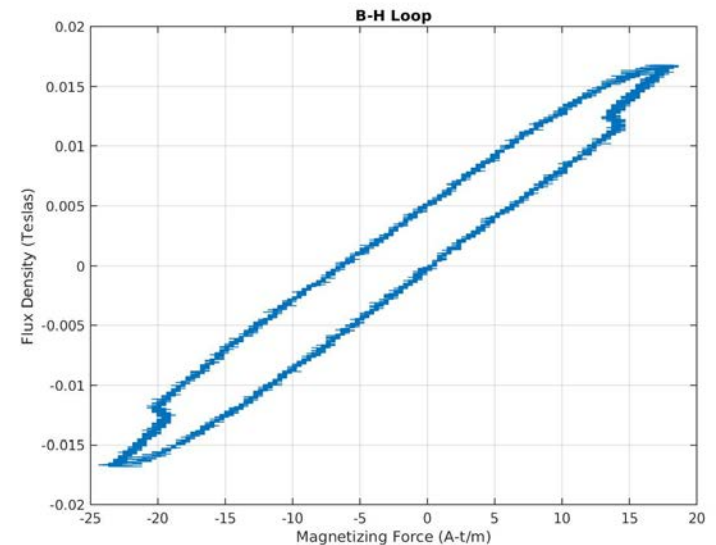
DVS Core Tester Verification: Air Core



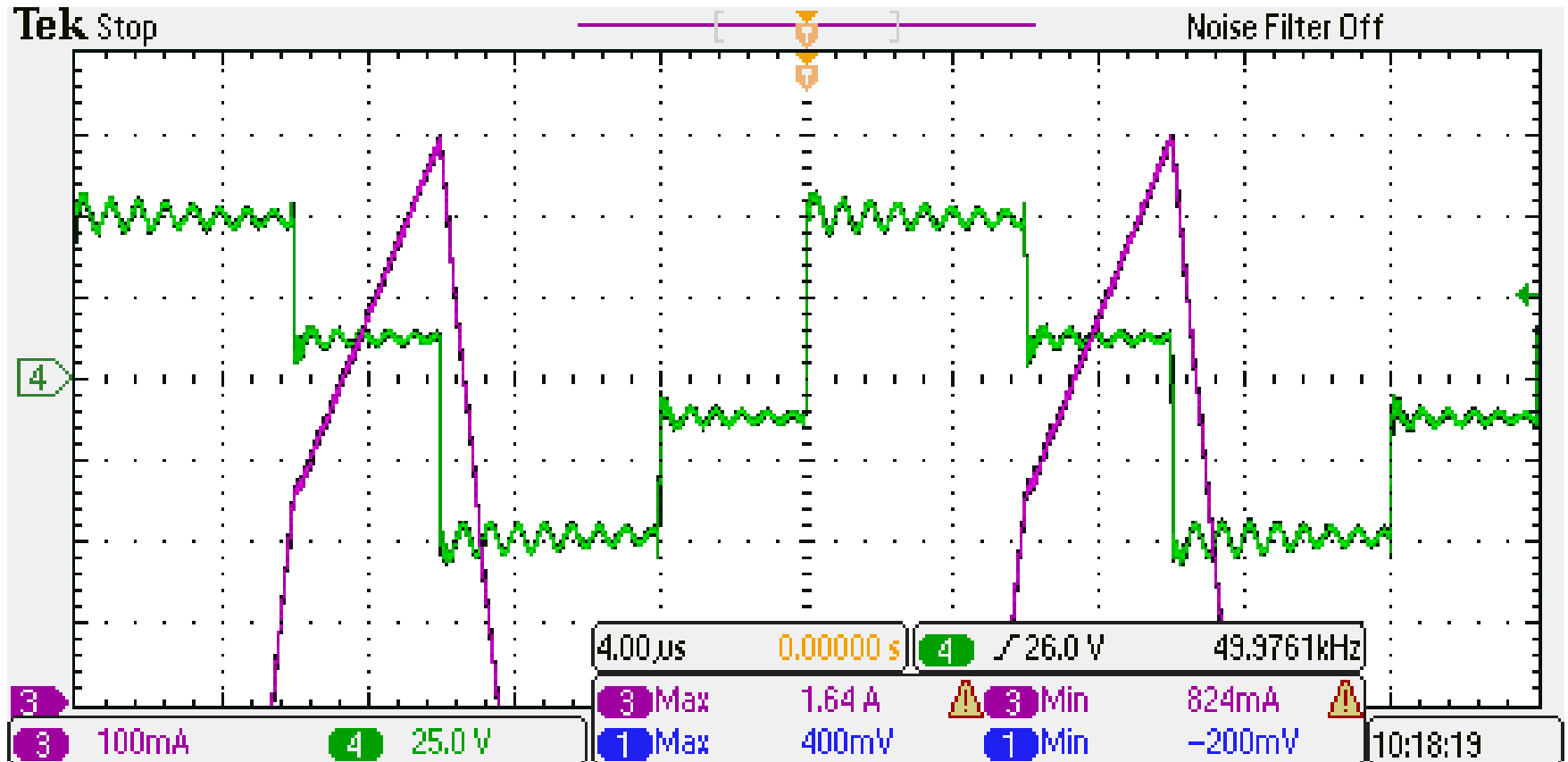
DVS Core Tester Verification: SiFe Core



Silicon Iron Core Inserted
Into Previous Inductor

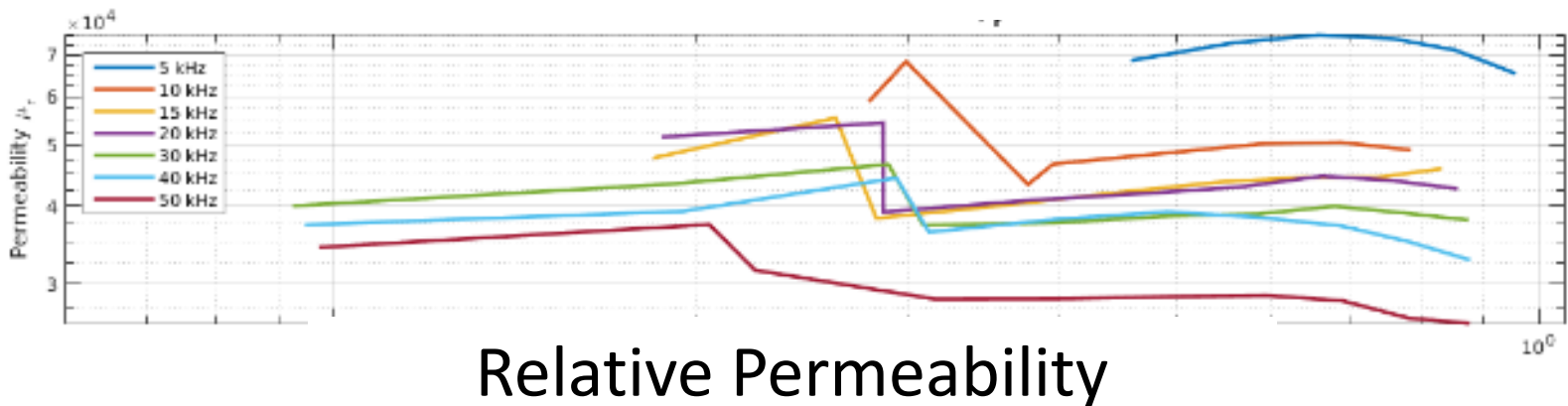
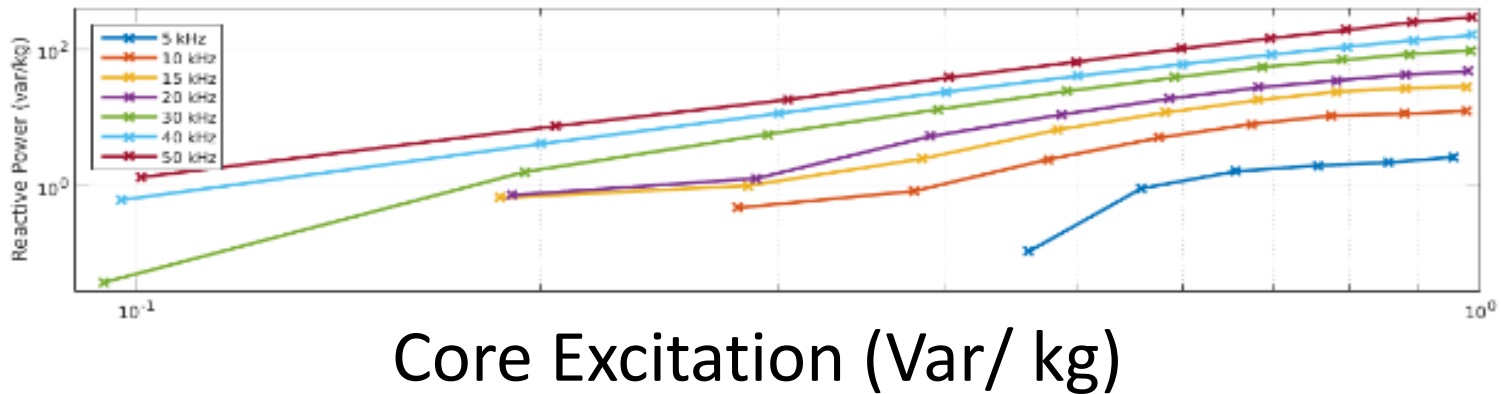
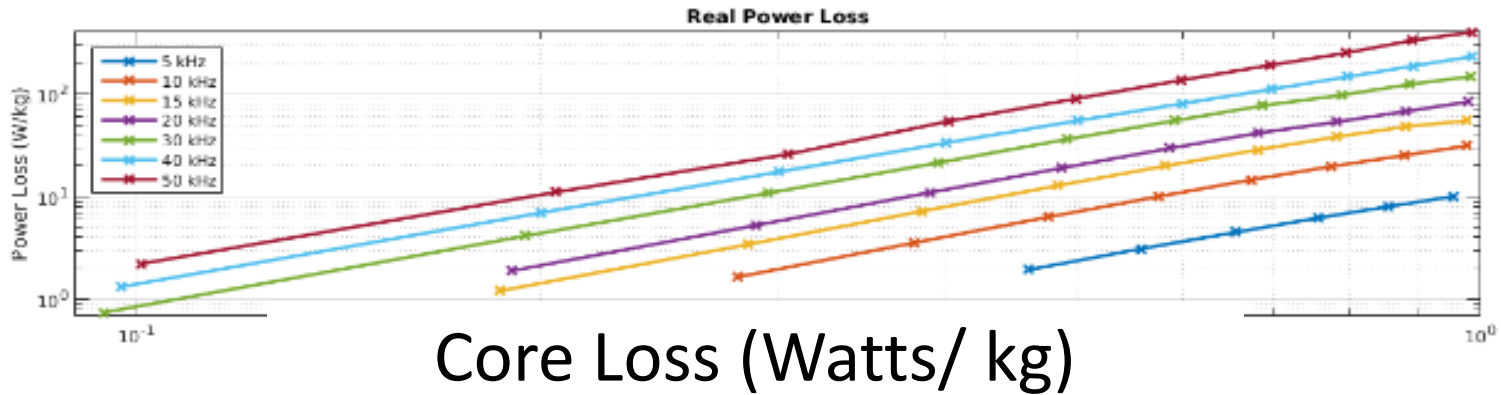


DVS Core Tester Verification: Air Core²

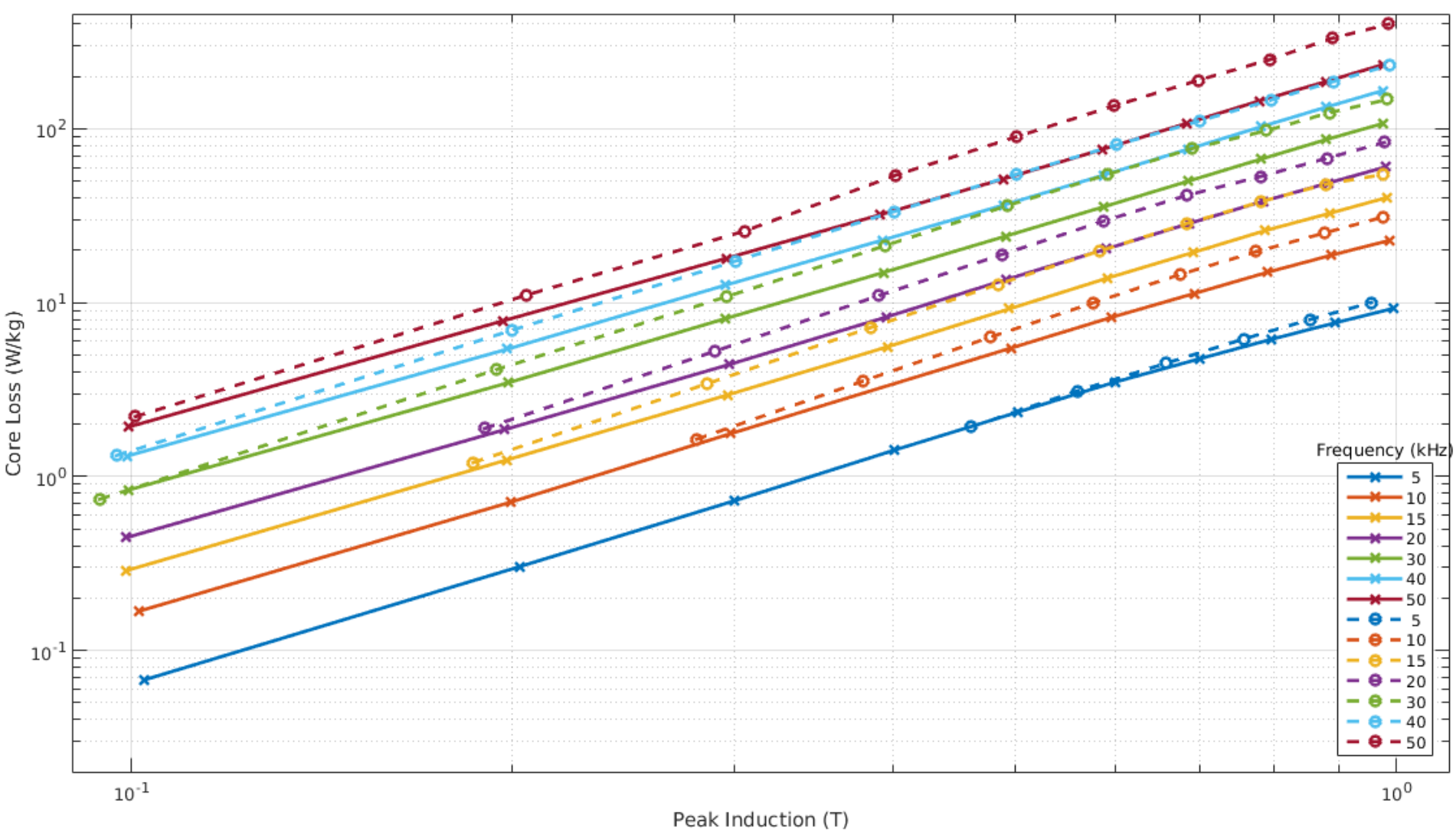


Silicon Iron Removed, Same Scaling on Scope

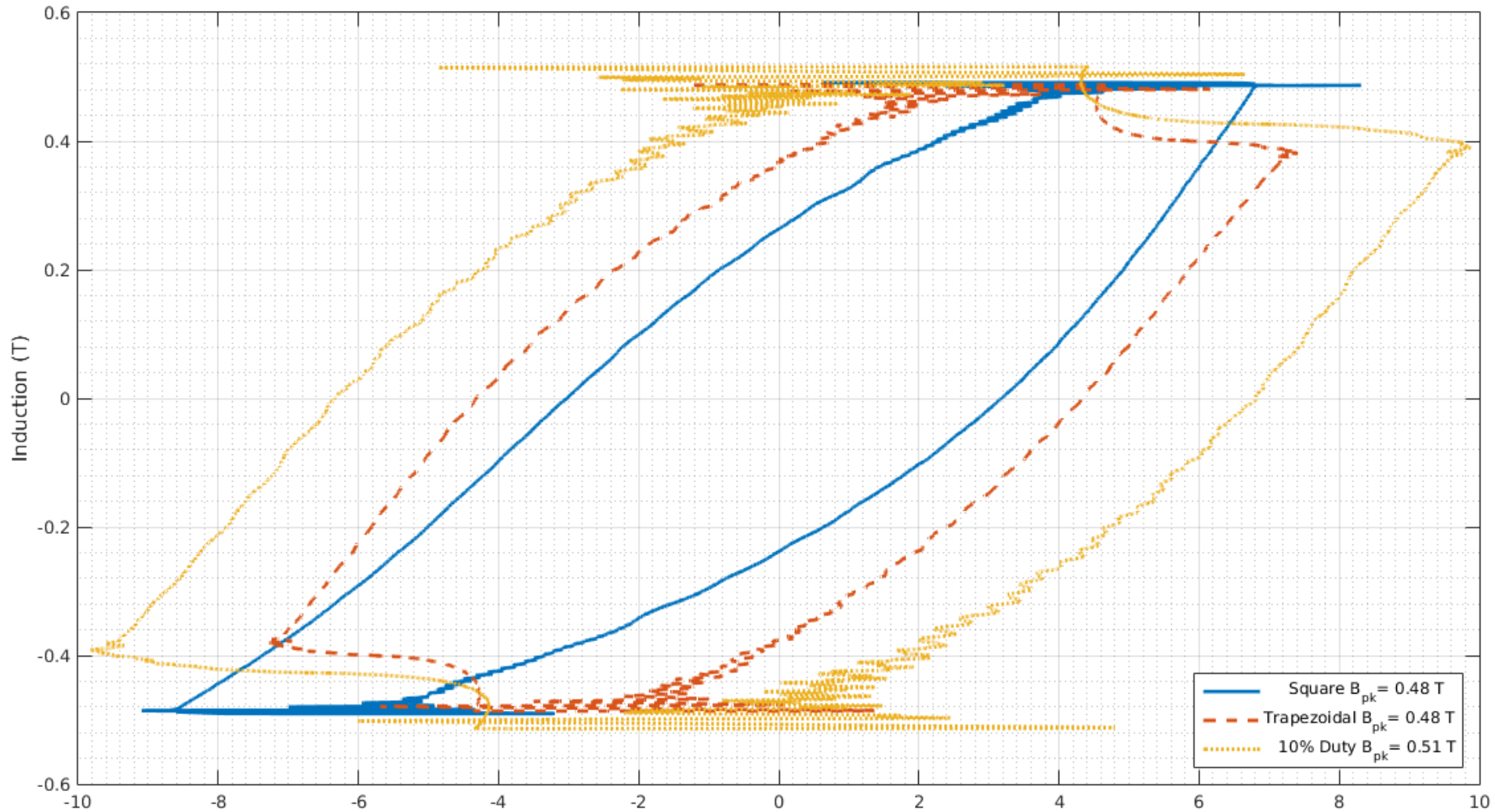
Core Characterization Map



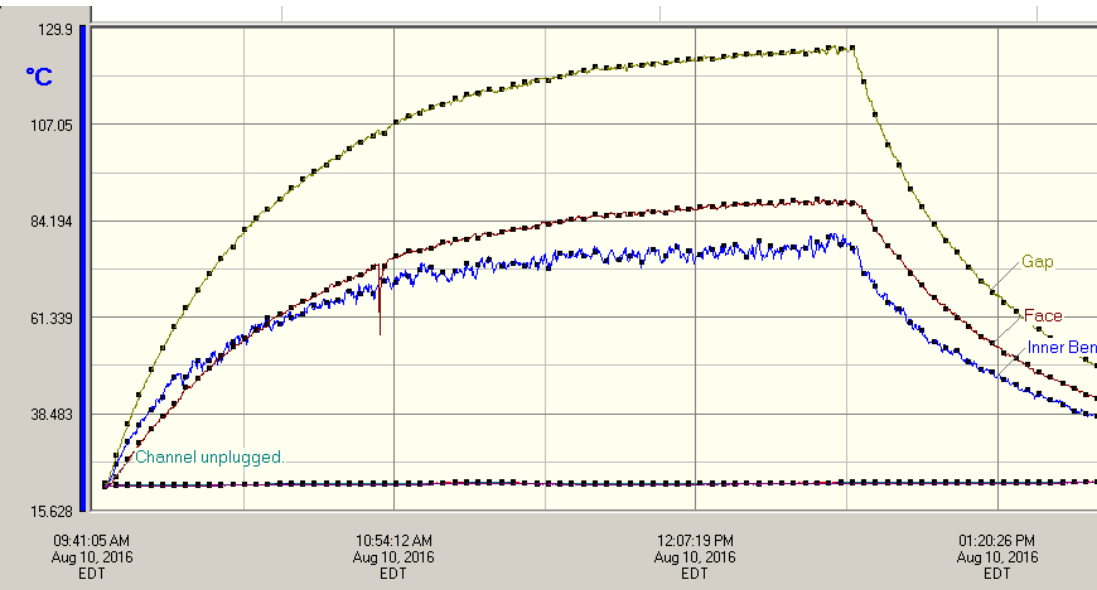
Loss Comparison: 50% vs 25% Duty



Hysteresis Comparison: 50% vs 25% vs 10% Duty Cycle ($B_{pk} = .5T$, 10 kHz)



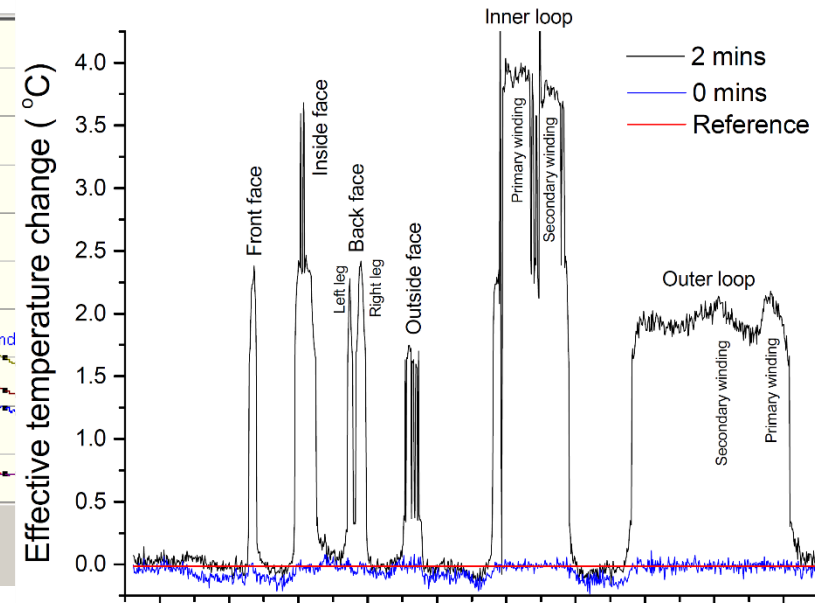
Thermal Characterization



Three Hour Run

Thermocouples

- Beveled Cut - Gold
- Inner Bend - Blue
- Center - Red

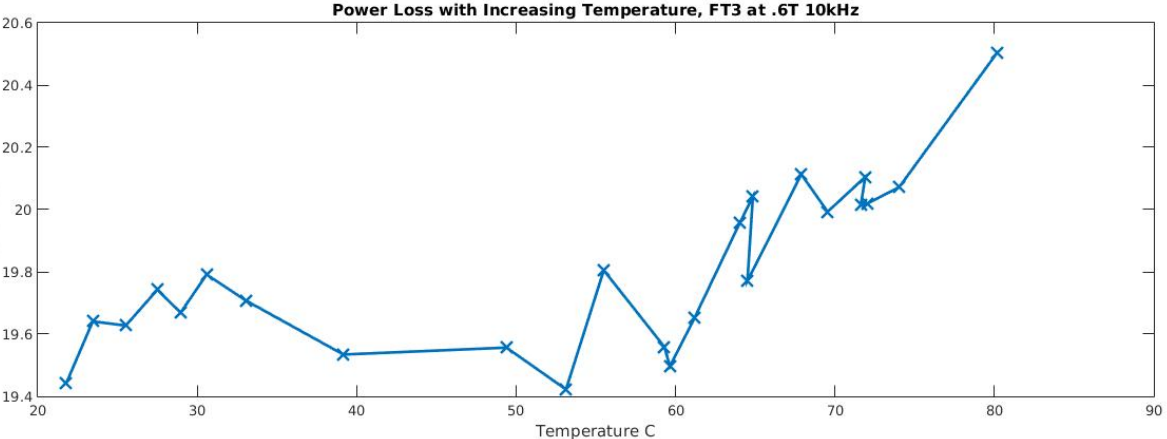


Advanced Thermals

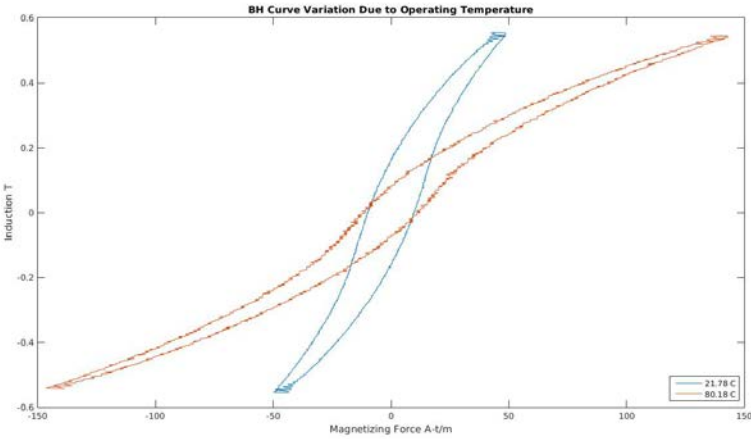
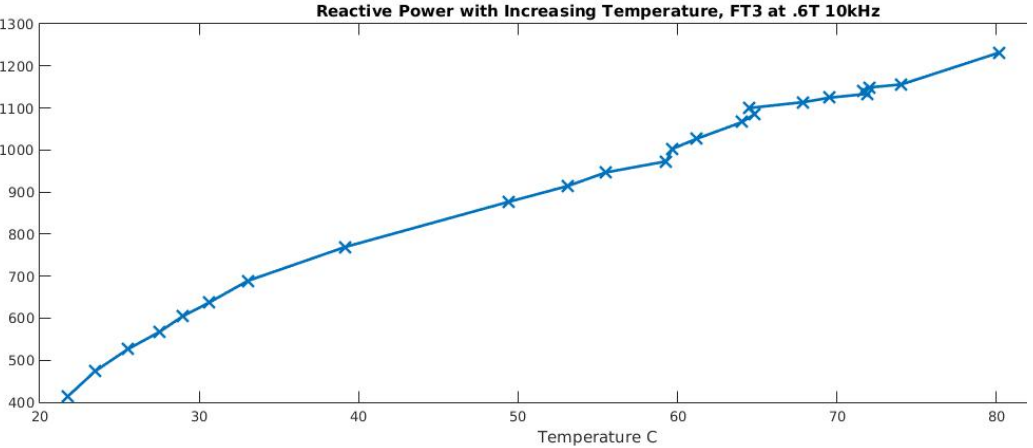
- Fiber Optic Strand
- Provides Temperature Profile

Provisional Patent: 62/606,160

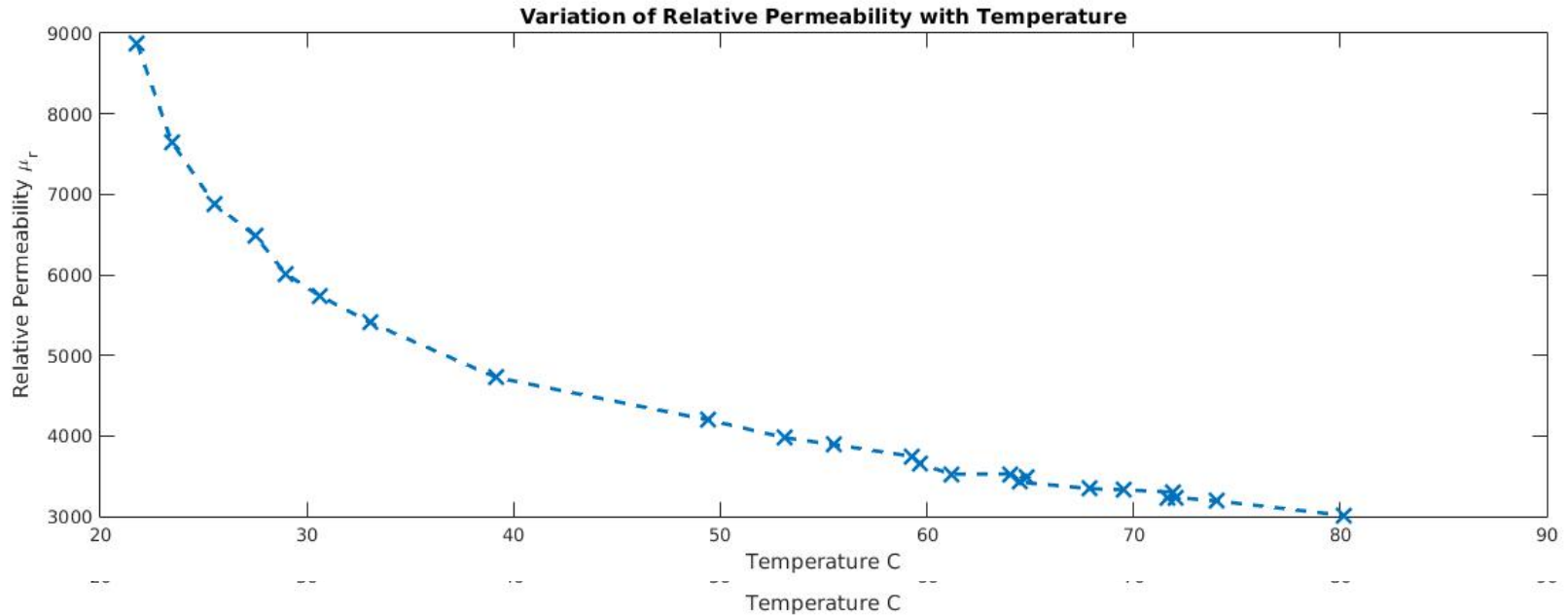
Core Parameter Variation for 22 C to 80 C Core Temperature Change



Constant 0.6 T Induction
Constant 10 kHz Frequency
6% Core Loss Variation
300% Magnetizing Power Variation
300% Relative Permeability Decrease



Thermal Decay of Permeability

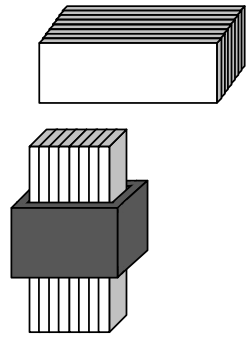


- Follows Q Variation
 - Min: 21.8C, $\mu_r = 8867$
 - Max: 80.2C, $\mu_r = 3013$
 - ~300% Decrease

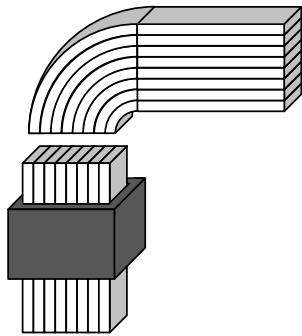
Medium Frequency Normal Flux Losses

Gap Fringing and Leakage

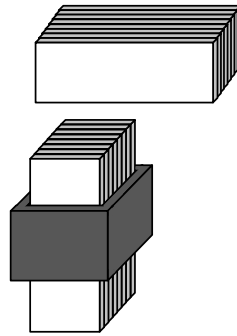
Ribbon Core Joints And Fringing



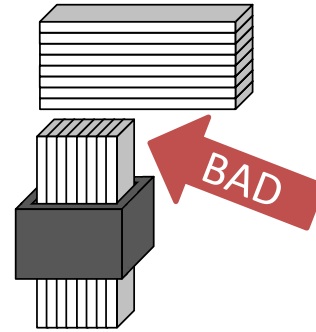
Rotated



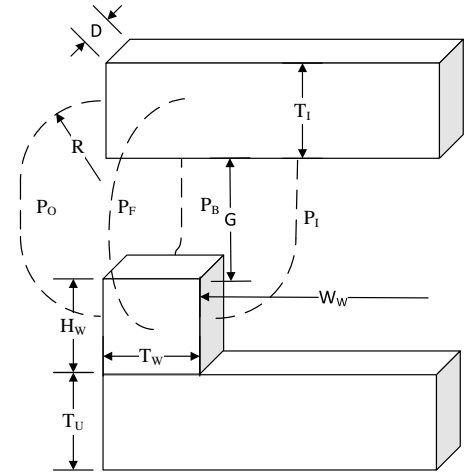
Wound



Edge to Edge



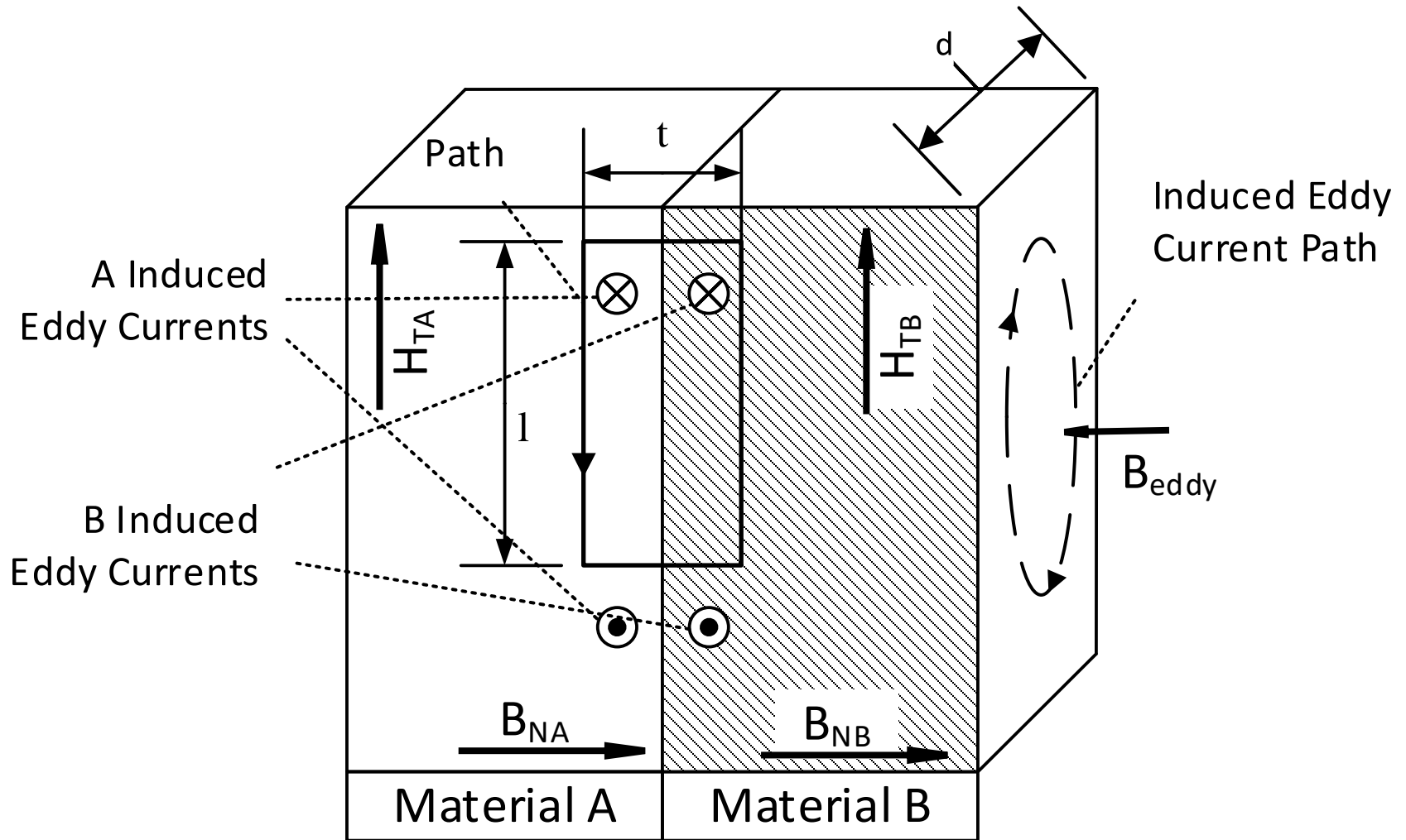
Face to Edge



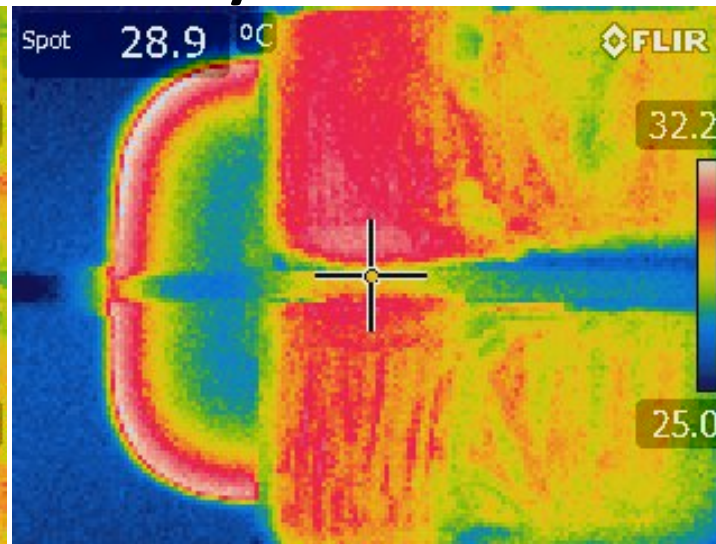
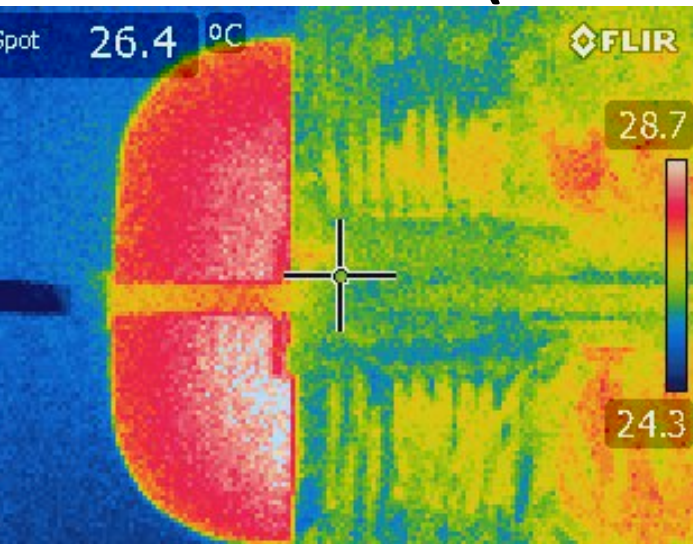
Core Connection	Magnetizing Flux	Window Leakage	Outer Leakage	Page Leakage	Inner Fringing	Outer Fringing	Page Fringing
Rotated	0	2	2	0	1	2	1
Wound	0	4	2	0	2	2	0
Edge on Edge	0	0	0	2	0	0	2
Face on Edge	1	4	2	0	2	1	0

The method of core joining has significant impact on leakage losses

Normal Flux Induced Eddy Currents



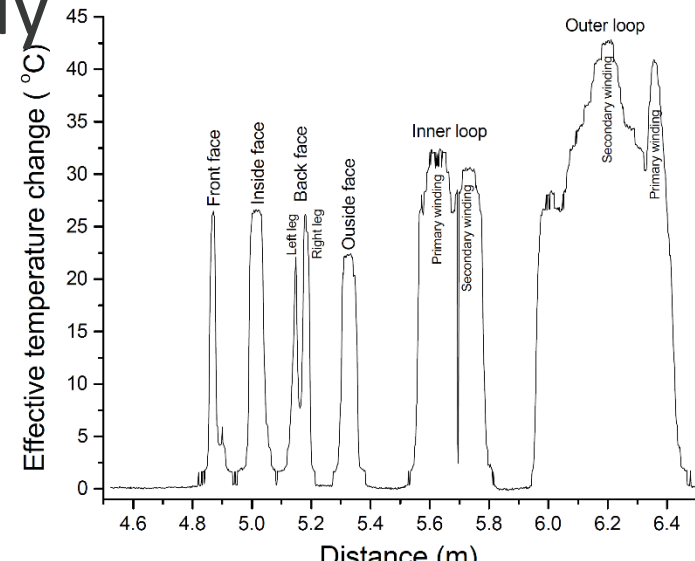
Leakage Test: Behaves Unexpectedly (Secondary is Shorted)



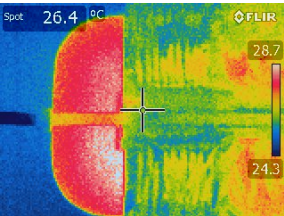
- Magnetizing
(For Reference)

• Leakage Study

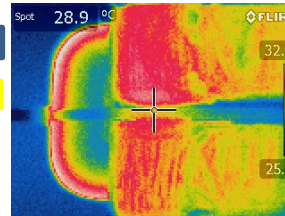
- Exterior Hot Gradient
- Unexpectedly High Losses



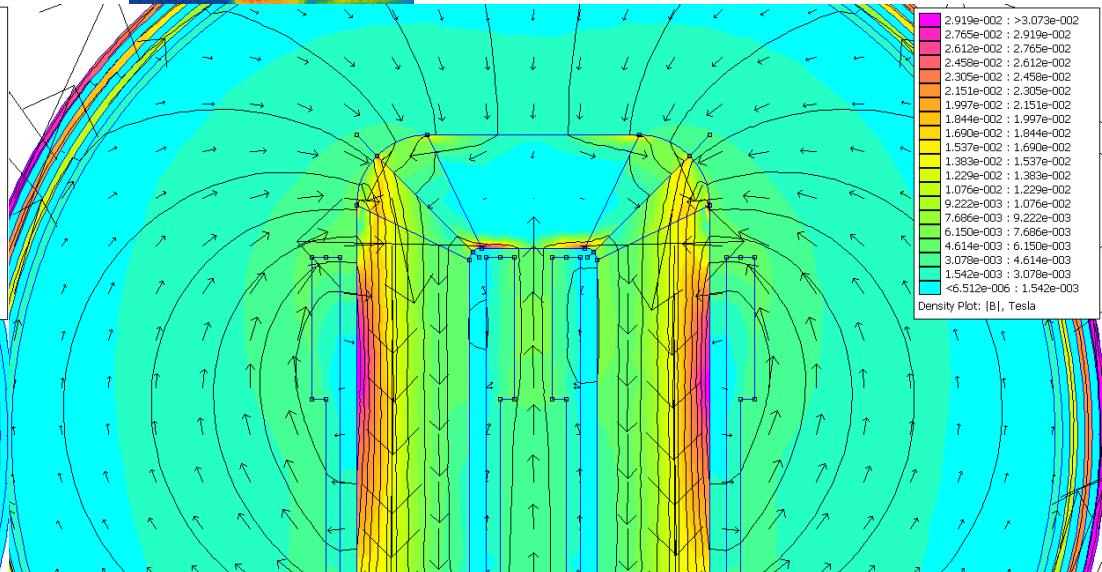
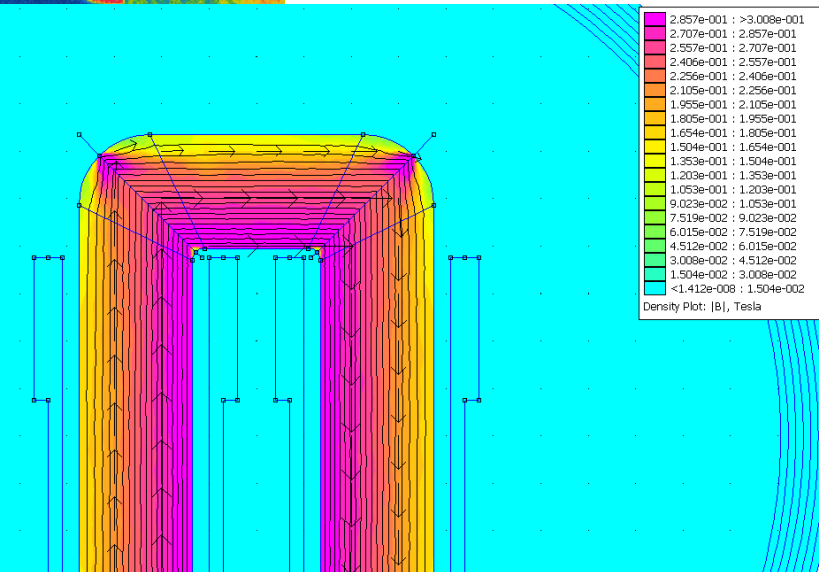
FEA Comparison of Magnetizing (Left) and Leakage (Right) Tests



- High B Inner Paths (0.3 T)
- Low B Outer Paths (0.009 T)

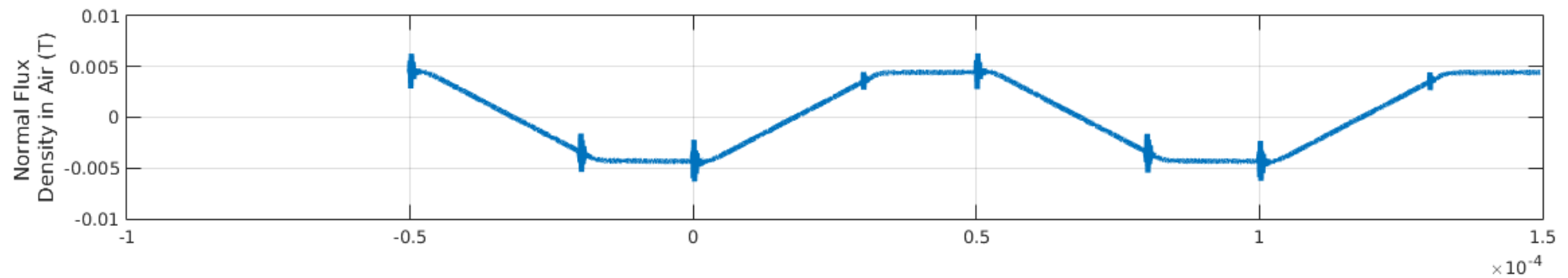
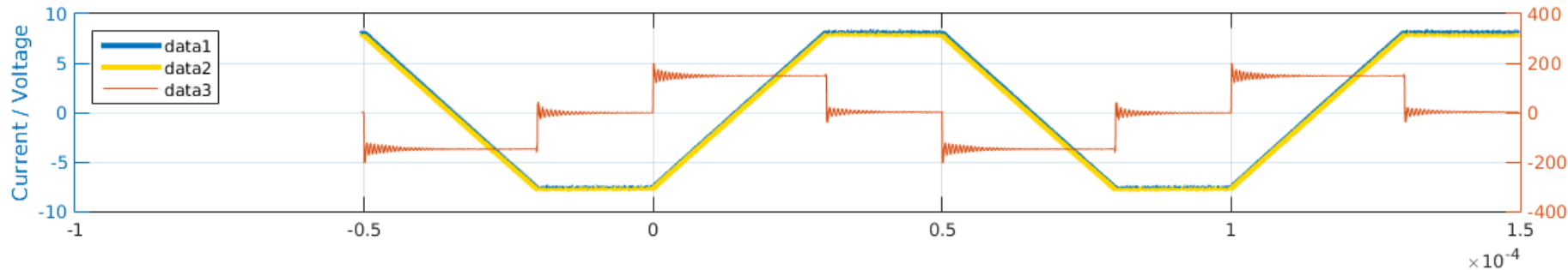


- High B Outer Surfaces (0.003 T)
- Low B Inner Regions (0.001 T)

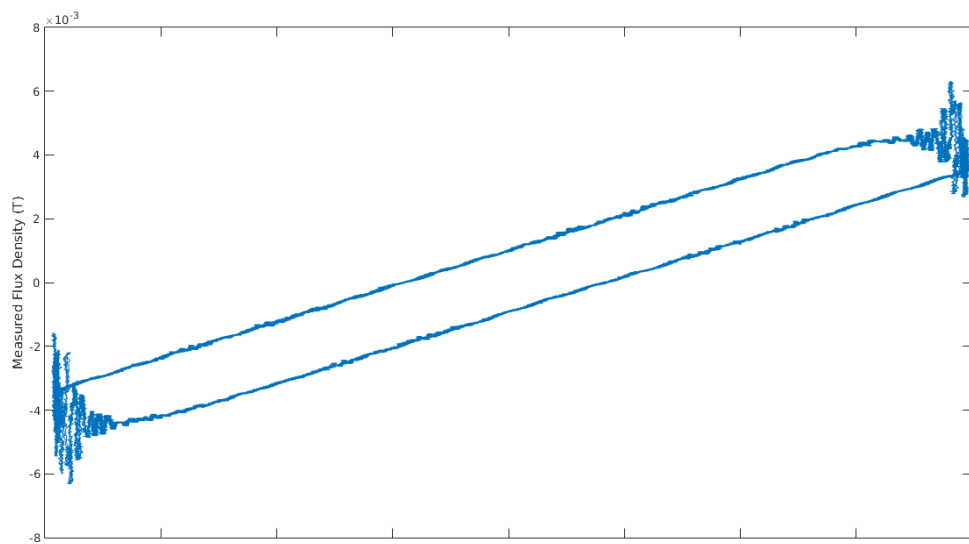


Short Circuit Test: Leakage Losses

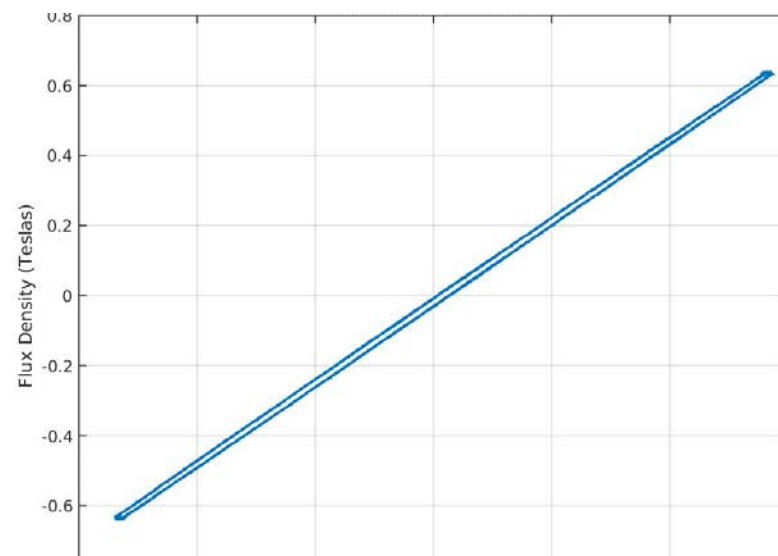
1: I primary, 2: I secondary, 3: V primary



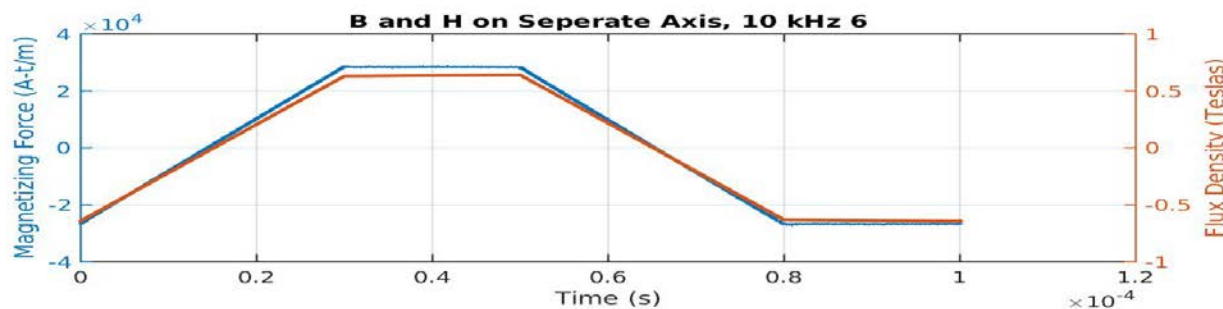
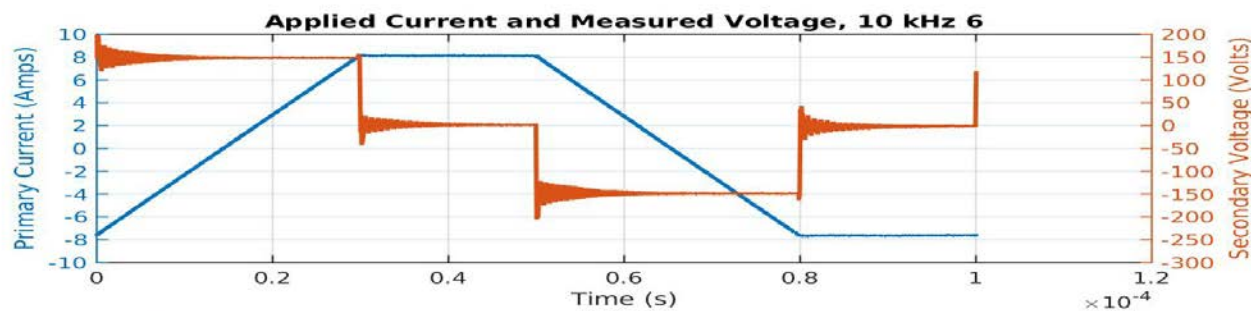
Loss Loops from Short Circuit Test



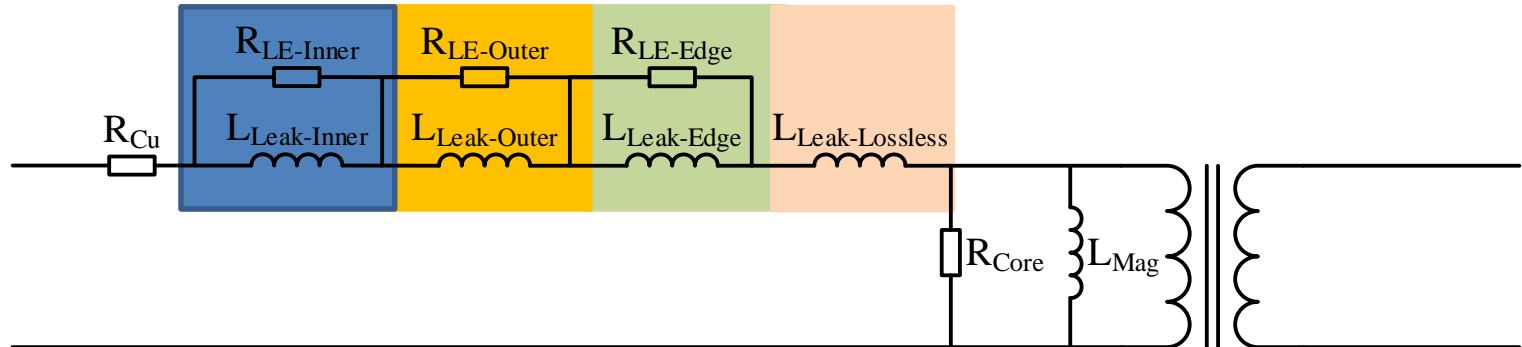
Flux Density Measured



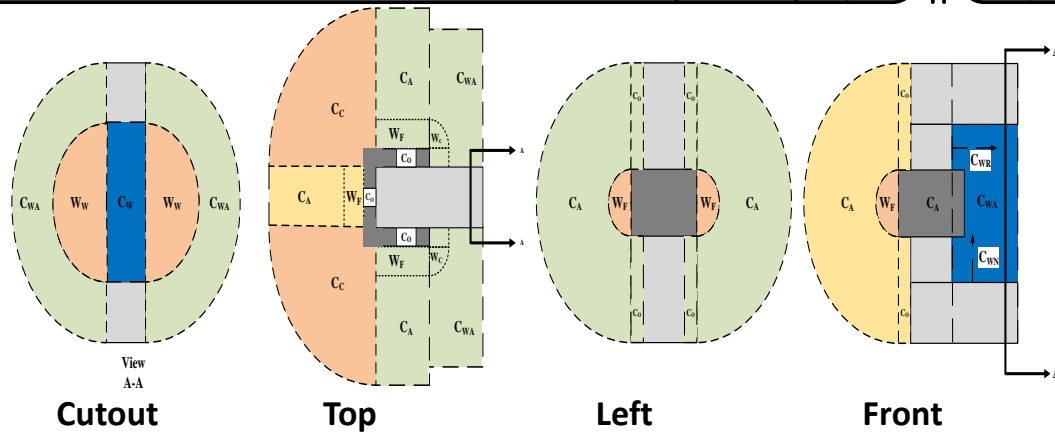
Flux Density Effective (Applied Voltage)



Proposed Leakage Loss Electrical Model



**Half Core
Flux Paths:**



Mix Material Shielding Solution
 Provisional Patent: 221404-8470, 62/582,107
 Paper Forthcoming

Core Loss Parameter Extraction

- Fit for Steinmetz

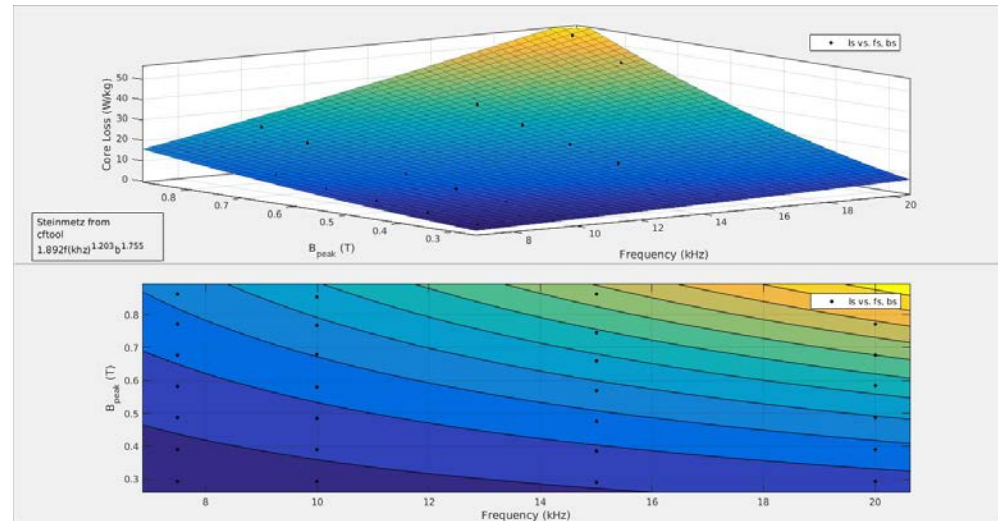
$$P_{V\text{Triangular}} = kf^\alpha B^\beta$$

- Three Point Extraction

$$\begin{bmatrix} P_1 \\ P_2 \\ P_3 \end{bmatrix} = \begin{bmatrix} 1 & \ln(f_1) & \ln(B_1) \\ 1 & \ln(f_2) & \ln(B_2) \\ 1 & \ln(f_3) & \ln(B_3) \end{bmatrix} \begin{bmatrix} \ln(k) \\ \alpha \\ \beta \end{bmatrix}$$

- Matlab

- Loss Surface Fitting
- Steinmetz Parameters
- Broader and More Accurate



Permeability Parameter Extraction

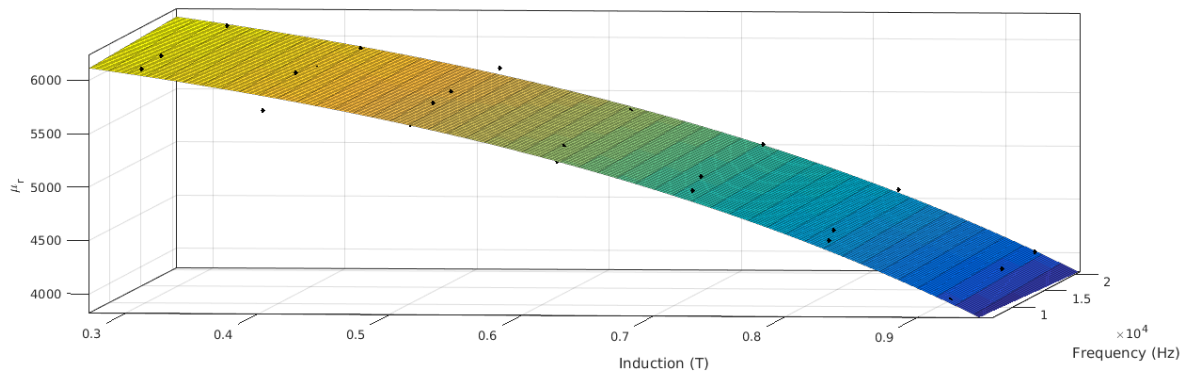
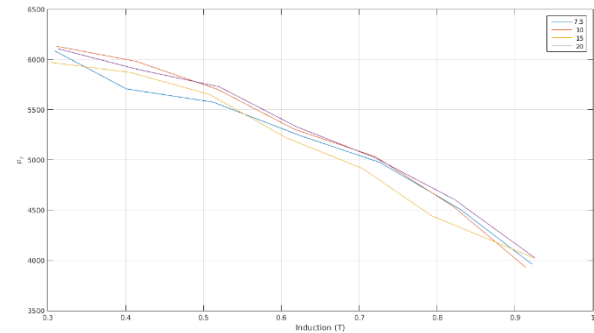
- No Defined Fit
- Polynomial
 - Requires Several Terms

$$\mu_r = \mu_c - \beta_1 B - \beta_2 B^2 + \beta_3 B^3$$

- Custom Equation
 - Natural Decay

$$\mu_r = \mu_c - \beta_1 e^{\beta_2 B}$$

- Sensitivity
 - Materials Differ
 - Induction Sensitivity
 - Frequency Sensitivity



Relevant Publications

R. Beddingfield, P. Vora, D. Storelli and S. Bhattacharya, "**Trapezoidal characterization of magnetic materials with a novel dual voltage test circuit**," 2017 IEEE Energy Conversion Congress and Exposition (ECCE), Cincinnati, OH, 2017, pp. 439-446.

R. Beddingfield, S. Bhattacharya, "**Multi-parameter Magnetic Material Characterization for High Power Medium Frequency Converters**", The Materials, Metals, & Materials Society (TMS) Supplemental Proceedings, 2017, 693-708

R. Beddingfield, D. Storelli and S. Bhattacharya, "**A novel dual voltage source converter for magnetic material characterization with trapezoidal excitation**," *2017 IEEE Applied Power Electronics Conference and Exposition (APEC)*, Tampa, FL, 2017, pp. 1659-1666.

Future Presentations / Papers

Application Impact of Magnetic Ribbon Core Strain Annealing (TMS 18)

Leakage Flux Induced Losses and Shielding in Magnetic (TMS 18)

Submissions to JMR and JOM

Acknowledgements:



Carnegie Mellon University



- DOE EERE SunShot Initiative SuNLaMP Program:
 - Combined PV / Battery Grid Integration with High Frequency Magnetics and Wide Bandgap Semiconductor Enabled Power Electronics (NETL Led)
- DOE EERE Advanced Manufacturing Office NGEM Program (Eaton Led)

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